

11 September 1998

Attention: Mr. Charlie Cobbs
Mr. Josef Dichoso

From: Shaik Raz
Israel Testing Laboratory

Refs: Application: MXN-890
Confirm. No: EA91546

Subject: a) Application MXN-MINT
Two) Mr. Cobbs' letter to Master Meter, Inc. dated Aug. 6, 1998

The subject E.U.T. was re-tested and a new application is being submitted,
Application: MXN-890 Confirm. No: EA91546

During the radiated emission re-testing, the E.U.T. orientation was carefully adjusted for maximum fundamental transmission level at the receiver antenna.

In addition, C23 capacitor was increased from 220 pF to 270 pF to reduce transmission harmonic levels.

Our new application is being submitted electronically. Please process it as soon as possible.

Sincerely,
Shaik Raz

Mr. Charlie Cobbs
Acting Chief, Equipment Authorization Division
FCC

Re: Denial of Application FCC# MXN-MINT
Ref: Denial letter sent August 6, 1998 to Master Meter, Inc.

Dear Mr. Cobbs,

ITL is the technical contact listed in form 731 for this application.

In the past, whenever there has been a problem with one of our client's applications, we have been contacted by the reviewing engineer. Following his comments, we performed the appropriate corrective actions, and sent him the new data by FAX. The new data was considered supplementary information to the original application.

Obviously, this was very convenient for our client and us. We believe that it was also convenient for the FCC.

In the above referenced letter, you specifically write that a new application is required. A new application, with the subsequent delay represents significant financial hardship for our client. Therefore, we kindly request a waiver for this requirement, and ask that we submit new *data as part of the original application, as we have done in the past.

Please bear in mind that our client needs to resolve this problem as soon as possible, so a timely response would be appreciated.

Thank you for your consideration of this matter.

I. Raz
EMC Laboratory Manager
ITL

*P.S. In the next few days we plan to re-test the E.U.T. and our test set-up.